PC3H3J00001H Series

Mini-flat Half Pitch Package, High CMR, AC Input Photocoupler



■ Description

PC3H3J00001H Series contains a IRED optically coupled to a phototransistor.

It is packaged in a 4-pin Mini-flat, Half pitch type. Input-output isolation voltage(rms) is 2.5kV. Collector-emitter voltage is 80V and CMR is MIN. 10kV/µs.

■ Features

- 1. 4-pin Mini-flat Half pitch package (Lead pitch: 1.27mm)
- 2. Double transfer mold package (Ideal for Flow Soldering)
- 3. AC input type
- 4. High collector-emitter voltage (V_{CEO}: 80V)
- 5. High noise immunity due to high common mode rejection voltage (CMR : MIN. 10kV/μs)
- 6. Isolation voltage between input and output (V_{iso(rms)}: 2.5kV)
- 7. RoHS directive compliant

■ Agency approvals/Compliance

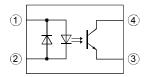
- 1.Recognized by UL1577 (Double protection isolation), file No. E64380 (as model No. **PC3H3**)
- 2. Package resin: UL flammability grade (94V-0)

■ Applications

1. Programmable controllers



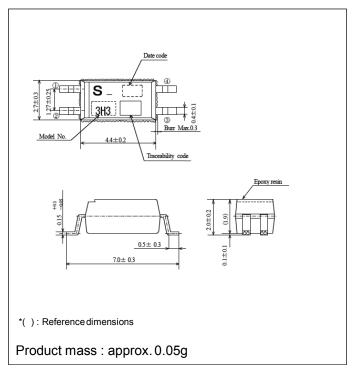
■ Internal Connection Diagram



- 1 Anode / Cathode
- ② Cathode / Anode
- ③ Emitter
- 4 Collector

■ Outline Dimensions







Date code indication (Ex.)

3-digit number shall be marked the age indication of 1-digit number, and week code of 2-digit number. Week code "01" indicate the week including the first Thursday of January. And later, Monday is the starting point.

Year	Week
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Date code	MON	TUE	WED	THU	FRI	SAT	SUN
652	12/26	12/27	12/28	12/29	12/30	12/31	1/1
701	1/2	1/3	1/4	1/5	1/6	1/7	1/8
702	1/9	1/10	1/11	1/12	1/13	1/14	1/15
703	1/16	1/17	1/18	1/19	1/20	1/21	1/22
•	•	•	•	•	•	•	•
	-	•	•	•	-	-	
		•	-	•			•
752	12/11	12/12	12/13	12/14	12/15	12/16	12/17
751	12/18	12/19	12/20	12/21	12/22	12/23	12/24
752	12/25	12/26	12/27	12/28	12/29	12/30	12/31
801	1/1	1/2	1/3	1/4	1/5	1/6	1/7

Country of origin and Plating material

Country of origin	Plating material
Japan	SnBi (Bi : 1∼4%)

Rank mark

Refer to the Model Line-up table.



■ Absolute Maximum Ratings

(T_a=25°C)

	Parameter	Symbol	Rating	Unit
	Forward current	I_F	±50	mA
Input	*1 Peak forward current	I_{FM}	±1	A
Ξ.	Power dissipation	P	70	mW
	Collector-emittervoltage	V_{CEO}	80	V
Output	Emitter-collector voltage	V _{ECO}	6	V
Out	Collector current	Ic	50	mA
	Collector power dissipation	P _C	150	mW
Total power dissipation		P _{tot}	170	mW
Operating temperature		Topr	-30 to +100	°C
Storage temperature		T_{stg}	-40 to +125	°C
*2 Isolation voltage		V _{iso (rms)}	2.5	kV
*3 S	Soldering temperature	T _{sol}	260	°C

■ Electro-optical Characteristics

(Ta=25°C)

	Parameter Symbol		Conditions	MIN.	TYP.	MAX.	Unit			
Langut	Forward voltage		Forward voltage		$V_{\rm F}$	$I_F=\pm 20 \text{mA}$	-	1.2	1.4	V
Input	Terminal capac	itance	Ct	V=0, f=1kHz	_	30	250	pF		
	Dark current		I _{CEO}	V _{CE} =50V, I _F =0	_	_	100	nA		
Output	Collector-emitte	er breakdown voltage	BV _{CEO}	$I_{C}=0.1 \text{mA}, I_{F}=0$	80	_	_	V		
	Emitter-collecte	or breakdown voltage	BV _{ECO}	$I_E=10\mu A, I_F=0$	6	_	_	V		
	Collector current I _C		$I_F=\pm 1 \text{ mA}, V_{CE}=5 \text{ V}$	0.2	_	4.0	mA			
Collector-emitter saturation voltage		er saturation voltage	V _{CE (sat)}	$I_F=\pm 20mA, I_C=1mA$	_	0.1	0.2	V		
	Isolation resistance		R _{ISO}	DC500V, 40 to 60%RH	5×10 ¹⁰	1×10 ¹¹	_	Ω		
Transfer	Floating capaci	tance	C_{f}	V=0, f=1MHz	_	0.6	1.0	pF		
charac- teristics	Dagmanga tima	Risetime	t _r	V 2V I 2m A	_	4	18	μs		
teristics	Response time	Falltime	t _f	V_{CE} =2V, I _C =2mA, R_{L} =100 Ω	_	3	18	μs		
	Common mode	Common mode rejection ratio		T_a =25°C, R_L =470 Ω , V_{CM} =1.5 kV (peak),	10	_	_	kV/μs		
			I _F =0, V _{CC} =9V, V _{np} =100mV							

^{*1} Pulse width≤100μs, Duty ratio : 0.001 *2 40 to 60%RH, AC for 1 minute, f=60Hz *3 For 10s



■ Model Line-up

Package	Taping	Rank mark	I _C [mA]	
	3,500pcs/reel	Kalikiliaik	$(I_{\text{E}}\pm 1\text{mA}, V_{\text{CE}}=5\text{V}, T_{\text{a}}=25^{\circ}\text{C})$	
Model No.	PC3H3J00001H	" " —	0.2 to 4.0	

Please contact a local SHARP sales representative to inquire about production status.



Fig.1 Forward Current vs. Ambient Temperature

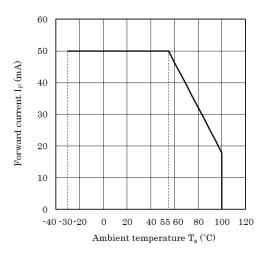


Fig.3 Collector Power Dissipation vs.
Ambient Temperature

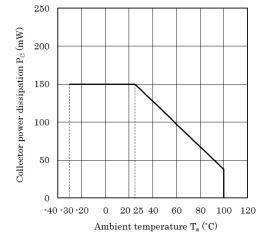


Fig.2 Diode Power Dissipation vs. Ambient Temperature

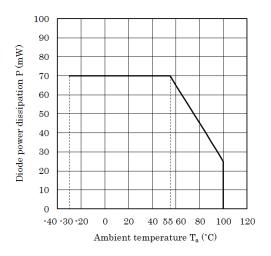


Fig.4 Total Power Dissipation vs. Ambient Temperature

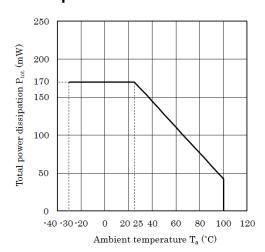


Fig.5 Peak Forward Current vs. Duty Ratio

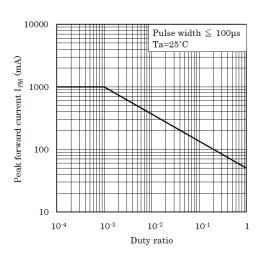
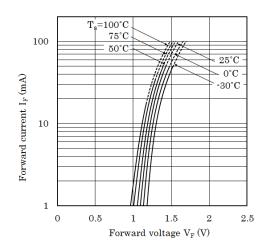


Fig.6 Forward Current vs. Forward Voltage



6



Fig.7 Current Transfer Ratio vs. Forward Current

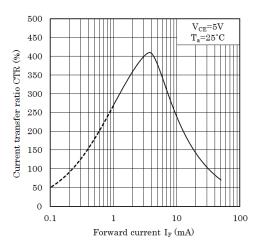


Fig.9 Relative Current Transfer Ratio vs.
Ambient Temperature

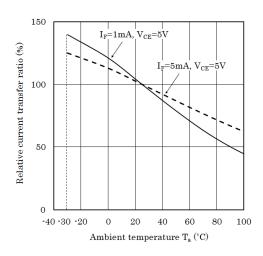


Fig.11 Collector Dark Current vs. Ambient Temperature

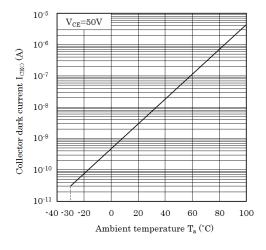


Fig.8 Forward Current vs. Forward Voltage

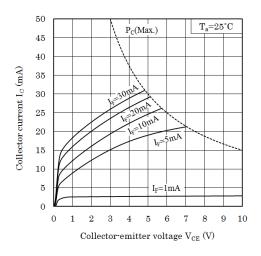


Fig.10 Collector - emitter Saturation Voltage vs. Ambient Temperature

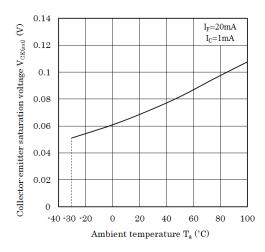


Fig.12 Collector-emitter Saturation Voltage vs. Forward Current

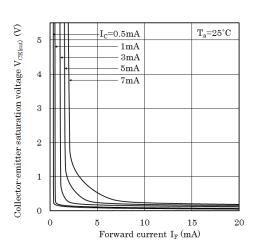




Fig.13 Response Time vs. Load Resistance

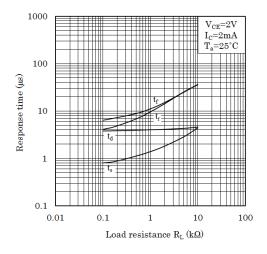


Fig.14 Test Circuit for Response Time

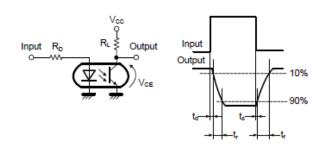


Fig.15 Frequency Response

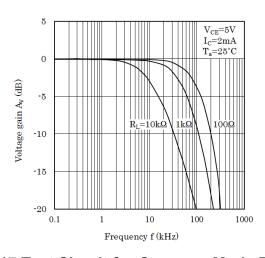


Fig.16 Test Circuit for Frequency Response

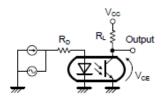
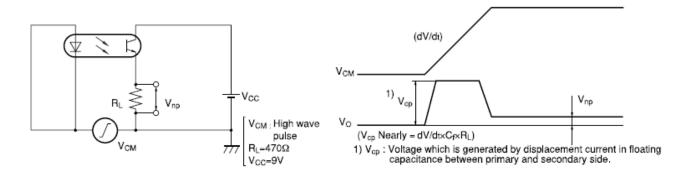


Fig.17 Test Circuit for Common Mode Rejection Voltage



Remarks: Please be aware that all data in the graph are just for reference and not for guarantee.



■ Design Considerations

• Design guide

While operating at I_F<1mA, CTR variation may increase.

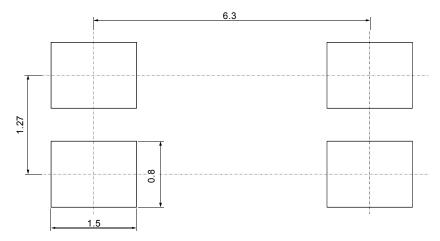
Please make design considering this fact.

This product is not designed against irradiation and incorporates non-coherent IRED.

Degradation

In general, the emission of the IRED used in photocouplers will degrade over time. In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

Recommended Foot Print (reference)



(Unit:mm)

☆ For additional design assistance, please review our corresponding Optoelectronic Application Notes.



■ Manufacturing Guidelines

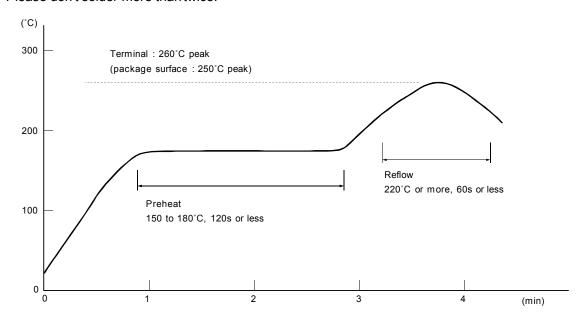
Soldering Method

Reflow Soldering:

Reflow soldering should follow the temperature profile shown below.

Soldering should not exceed the curve of temperature profile and time.

Please don't solder more than twice.



Flow Soldering:

Due to SHARP's double transfer mold construction submersion in flow solder bath is allowed under the below listed guidelines.

Flow soldering should be completed below 260°C and within 10s.

Preheating is within the bounds of 100 to 150°C and 30 to 80s.

Please don't solder more than twice.

Hand soldering

Hand soldering should be completed within 3s when the point of solder iron is below 400°C.

Please don't solder more than twice.

Other notice

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the tooling and soldering conditions.



Cleaning instructions

Solvent cleaning:

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

Ultrasonic cleaning:

The impact on the device varies depending on the size of the cleaning bath, ultrasonic output, cleaning time, size of PCB and mounting method of the device.

Therefore, please make sure the device withstands the ultrasonic cleaning in actual conditions in advance of mass production.

Recommended solvent materials:

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

In case the other type of solvent materials are intended to be used, please make sure they work fine in actual using conditions since some materials may erode the packaging resin.

Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this product.

Regulation substances: CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBB and PBDE are not used in this product at all.

- The RoHS directive(2011/65/EU)
 This product complies with the RoHS directive(2011/65/EU)
 Object substances: mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls
 (PBB) and polybrominated diphenyl ethers (PBDE)
- (2) Content of six substances specified in Management Methods for Control of Pollution Caused by Electronic Information Products Regulation (Chinese: 电子信息产品污染控制管理办法).

Marking Styles for the Names and Contents of the Hazardous Substances

	Hazardous Substances						
Category	Lead (Pb)	Mercury (Hg)	Cadmium (Cd)	Hexavalent chromium (Cr ⁶⁺)	Polybrominated biphenyls (PBB)	Polybrominated diphenyl ethers (PBDE)	
Photocoupler	0	0	0	0	0	0	

This table is prepared in accordance with the provisions of SJ/T 11364.

• : Indicates that said hazardous substance contained in all of the homogeneous materials for this part is below the limit requirement of GB/T 26572.



■ Package specification

● Tape and Reel package

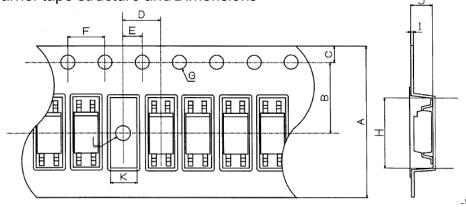
Package materials

Carrier tape: PS

Cover tape: PET (three layer system)

Reel: PS

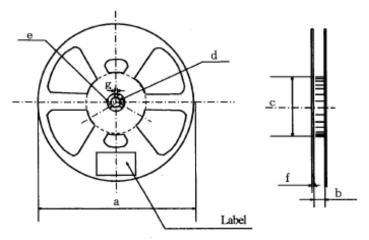
Carrier tape structure and Dimensions



Dimensions List (Unit: mm)

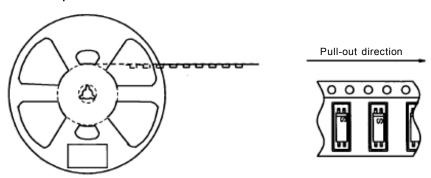
Α	В	С	D	Е	F	G
16.0±0.3	$7.5^{\pm0.1}$	1.75 ^{±0.1}	4.0 ^{±0.1}	2.0±0.1	4.0 ^{±0.1}	\$\dphi 1.5^{+0.1}_{-0.0}\$
Н	I	J	K	L		
$7.55^{\pm0.1}$	0.3	2.3 ^{±0.1}	$2.85^{\pm0.1}$	ф1.55 ^{±0.1}		

Reel structure and Dimensions



Dimensio	ns List	(Unit: mm)		
a	b	с	d	
φ330±2.0	17.5 ^{±1.0}	$\phi 100.0^{\pm 1.0}$	ф13.0 ^{±0.2}	
e	f	g		
\$\dphi21.0\pmu0.8\$	2.0±0.5	2.0±0.5		

Direction of product insertion



[Packing: 3,500pcs/reel]



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 - --- Office automation equipment
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- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.
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